

ABSTRACT OF THE DISCLOSURE

The invention includes an integrated circuit (IC). The IC may include an internal test bus (ITB). The IC may also include a number of deskew clusters connected to the ITB.

- 5 The deskew clusters each include a deskew controller. The IC may also include an integrated test controller (ITC) connected to the ITB. Further, the IC may include a debug unit connected to the ITC. The ITC generates a single global control signal and the deskew controller generates a first
- 10 local command signal.